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Webb, C.F.; Anderson, C.J.; Sigal, L.; Shepard, K.L.; Liptay, J.S.; Warnock, J.D.; Curran, B.; Krumm, B.W.; Mayo, M.D.; Camporese, P.J.; Schwarz, E.M.; Farrell, M.S.; Restle, P.J.; Averill, R.M., III; Slegel, T.J.; Houtt, W.V.; Chan, Y.H.; Wile, B.; Nguyen, T.N.; Emma, P.G.; Beece, D.K.; Ching-Te Chuang; Price, C.;
 Solid-State Circuits, IEEE Journal of , Volume: 32 , Issue: 11 , Nov. 1997
 Pages:1665 - 1675

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2 **Upset-like fault injection in VHDL descriptions: A method and preliminary results**

Velazco, R.; Leveugle, R.; Calvo, O.;
 Defect and Fault Tolerance in VLSI Systems, 2001. Proceedings. 2001 IEEE International Symposium on , 24-26 Oct. 2001
 Pages:259 - 267

[\[Abstract\]](#) [\[PDF Full-Text \(170 KB\)\]](#) **IEEE CNF**

3 **A Study of Random Channel Errors for an ADM System**

Prezas, D.; LoCicero, J.;
 Communications, IEEE Transactions on [legacy, pre - 1988]
 , Volume: 29 , Issue: 2 , Feb 1981
 Pages:117 - 122

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4 A programmable gate array based integrated circuit for high bit rate telecommunications transmission system applications

Mallett, C.T.; Tomkins, J.W.; Nagra, A.S.T.;

Solid-State Circuits, IEEE Journal of , Volume: 17 , Issue: 3 , Jun 1982

Pages:586 - 588

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Communications Magazine, IEEE , Volume: 20 , Issue: 5 , Sep 1982

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Communications Magazine, IEEE , Volume: 24 , Issue: 4 , Apr 1986

Pages:50 - 51

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7 A Compact 4-GHz Linearize for Space Use

Inada, R.; Ogawa, H.; Kitazume, S.; Desantis, P.;

Microwave Theory and Techniques, IEEE Transactions on , Volume: 34 , Issue: 12 , Dec 1986

Pages:1327 - 1332

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8 ErrorTracer: design error diagnosis based on fault simulation techniques

Shi-Yu Huang; Kwang-Ting Cheng;

Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on , Volume: 18 , Issue: 9 , Sept. 1999

Pages:1341 - 1352

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9 REMOD: a new methodology for designing fault-tolerant arithmetic circuits

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Very Large Scale Integration (VLSI) Systems, IEEE Transactions on , Volume: 5 , Issue: 1 , March 1997

Pages:34 - 56

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10 Framework for testing the fault-tolerance of systems including OS and network aspects

Buchacker, K.; Sieh, V.;

High Assurance Systems Engineering, 2001. Sixth IEEE

International Symposium on , 22-24 Oct. 2001
Pages:95 - 105

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